

#### P-CHANNEL ENHANCEMENT MODE MOSFET

#### **Product Summary**

BV <sub>DSS</sub>	R <sub>DS(ON)</sub> Max	I <sub>D</sub> Max T <sub>A</sub> = +25°C		
-20V	$33m\Omega$ @ $V_{GS} = -4.5V$	-7.0A		
-20V	$52mΩ @ V_{GS} = -2.5V$	-5.5A		

### **Features and Benefits**

- Low On-Resistance
- Low Gate Threshold Voltage
- Low Input Capacitance
- Fast Switching Speed
- Low Input/Output Leakage
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)

## **Description and Applications**

This MOSFET is designed to minimize the on-state resistance ( $R_{DS(ON)}$ ) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

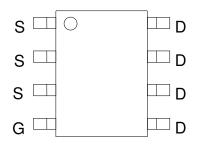
- Backlighting
- Power Management Functions
- DC-DC Converters

#### **Mechanical Data**

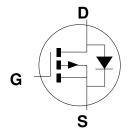
- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound.
   UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals Connections: See Diagram
- Terminals: Finish Matte Tin Annealed over Copper Lead Frame. Solderable per MIL-STD-202, Method 208 <sup>®</sup>3
- Weight: 0.072g (Approximate)







Top View Pin-Out



**Equivalent Circuit** 

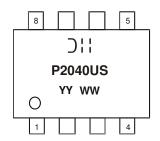
#### Ordering Information (Note 4)

Part Number	Case	Packaging
DMP2040USS-13	SO-8	2500/Tape & Reel

Notes:

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant.
- See https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. For packaging details, go to our website at https://www.diodes.com/design/support/packaging/diodes-packaging/.

## **Marking Information**



);; = Manufacturer's Marking
P2040US = Product Type Marking Code
YYWW = Date Code Marking
YY or YY = Year (ex: 19 = 2019)
WW = Week (01 to 53)



#### **Maximum Ratings** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit		
Drain-Source Voltage			V <sub>DSS</sub>	-20	V
Gate-Source Voltage			$V_{GSS}$	±12	V
Continuous Drain Current (Note C) V 4 5V	Steady	T <sub>A</sub> = +25°C	I-	-7.0	A
Continuous Drain Current (Note 6) V <sub>GS</sub> = -4.5V	State	T <sub>A</sub> = +70°C	I <sub>D</sub>	-5.5	
Continuous Dunin Comment (Nata 7) // 4 5)/	Steady	T <sub>C</sub> = +25°C	,	-15	А
Continuous Drain Current (Note 7) V <sub>GS</sub> = -4.5V	State	T <sub>C</sub> = +70°C	I <sub>D</sub>	-12	
Pulsed Drain Current (10µs Pulse, Duty Cycle = 1%)	I <sub>DM</sub>	-30	Α		
Continuous Source-Drain Diode Current (Note 6)			Is	-2.2	Α
Avalanche Current (Note 8) L = 0.1mH			I <sub>AS</sub>	-16	Α
Avalanche Energy (Note 8) L = 0.1mH			Eas	13.5	mJ

#### Thermal Characteristics (@TA = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit	
Total Power Dissipation (Note 5)	$T_A = +25^{\circ}C$	P <sub>D</sub>	1.4	W
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	$R_{\theta JA}$	91	°C/W
Total Power Dissipation (Note 6)	$T_A = +25^{\circ}C$	P <sub>D</sub>	1.9	W
Thermal Resistance, Junction to Ambient (Note 6)	Steady State	$R_{\theta JA}$	64	°C/W
Thermal Resistance, Junction to Case (Note 7)  Steady State		R <sub>0JC</sub>	13.5	°C/W
Operating and Storage Temperature Range		$T_{J_i}T_{STG}$	-55 to +150	°C

# **Electrical Characteristics** (T<sub>A</sub> = +25°C, unless otherwise specified.)

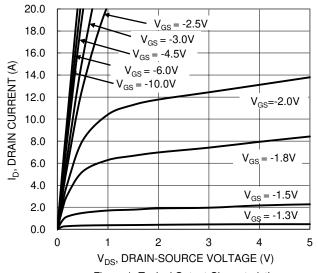
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 9)							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-20	_	_	V	$V_{GS} = 0V, I_D = -250\mu A$	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	_	-1	μΑ	V <sub>DS</sub> = -16V, V <sub>GS</sub> = 0V	
Gate-Source Leakage	I <sub>GSS</sub>	_	_	±100	nA	$V_{GS} = \pm 12V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 9)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	-0.6	_	-1.5	V	$V_{DS} = V_{GS}$ , $I_D = -250\mu A$	
Static Drain-Source On-Resistance	D	— 26 33 mΩ	$V_{GS} = -4.5V, I_D = -8.9A$				
Static Dialif-Source Off-nesistance	R <sub>DS(ON)</sub>	_	37.5	52	mΩ	$V_{GS} = -2.5V, I_D = -6.9A$	
Diode Forward Voltage	$V_{SD}$	_	-0.7	-1.2	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = -2.9A	
DYNAMIC CHARACTERISTICS (Note 10)							
Input Capacitance	Ciss		834	_		V <sub>DS</sub> = -10V, V <sub>GS</sub> = 0V, f = 1.0MHz	
Output Capacitance	Coss	_	133	_	pF		
Reverse Transfer Capacitance	C <sub>rss</sub>	_	105	_			
Gate Resistance	Rg	_	4.9	_	Ω	$V_{DS} = 0V$ , $V_{GS} = 0V$ , $f = 1.0MHz$	
Total Gate Charge (V <sub>GS</sub> = -4.5V)	$Q_g$	_	8.6	_			
Total Gate Charge (V <sub>GS</sub> = -8V)	Qg	_	19	_	nC	$V_{DS} = -6V, I_D = -8.9A$	
Gate-Source Charge	Q <sub>gs</sub>	_	1.5	_	110		
Gate-Drain Charge	Q <sub>gd</sub>	_	2.5	_			
Turn-On Delay Time	t <sub>D(ON)</sub>	_	5.8	_			
Turn-On Rise Time	t <sub>R</sub>	_	7.7	_	no	$\begin{aligned} V_{DD} &= \text{-6V}, \ R_L = 6\Omega \\ V_{GS} &= \text{-4.5V}, \ R_g = 6\Omega, \ I_D = \text{-1A} \end{aligned}$	
Turn-Off Delay Time	t <sub>D(OFF)</sub>	_	28.1	_	ns		
Turn-Off Fall Time	t <sub>F</sub>	-	14.6	_			
Body Diode Reverse Recovery Time	t <sub>RR</sub>	-	9.8	_	ns	I <sub>F</sub> = -8.9A, di/dt = -100A/μs	
Body Diode Reverse Recovery Charge	Q <sub>RR</sub>		2.7	_	nC	$I_F = -8.9A$ , $di/dt = -100A/\mu s$	

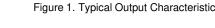
Notes:

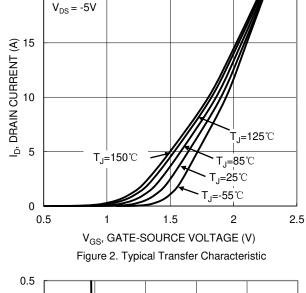
- 5. Device mounted on FR-4 PC board, with minimum recommended pad layout, single sided.6. Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate.
- 7. Thermal resistance from junction to soldering point (on the exposed drain pad).
- 8.  $I_{AS}$  and  $E_{AS}$  ratings are based on low frequency and duty cycles to keep  $T_J$  = +25°C.
- 9. Short duration pulse test used to minimize self-heating effect.
- 10. Guaranteed by design. Not subject to product testing.











20

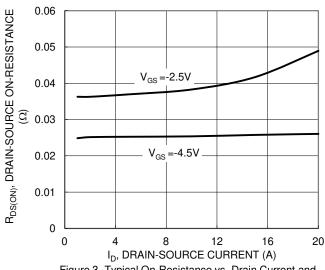


Figure 3. Typical On-Resistance vs. Drain Current and Gate Voltage

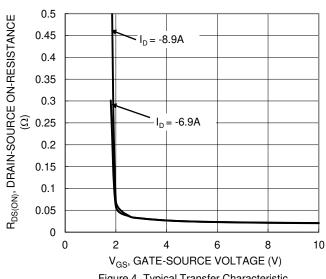


Figure 4. Typical Transfer Characteristic

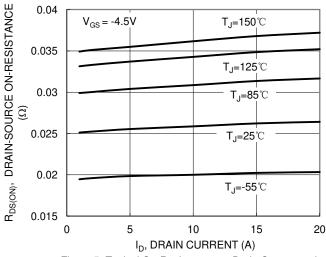


Figure 5. Typical On-Resistance vs. Drain Current and Junction Temperature

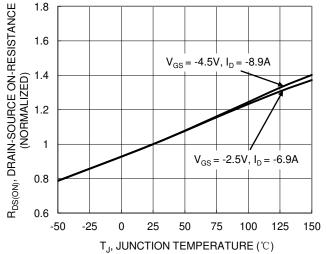


Figure 6. On-Resistance Variation with Junction **Temperature** 



### DMP2040USS

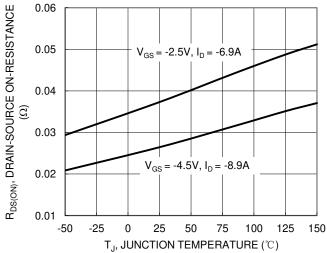


Figure 7. On-Resistance Variation with Junction Temperature

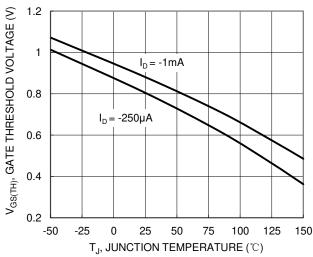
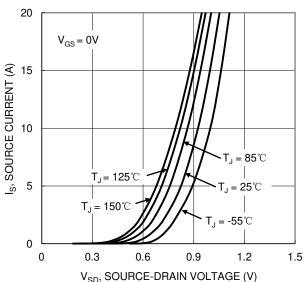


Figure 8. Gate Threshold Variation vs. Junction Temperature



V<sub>SD</sub>, SOURCE-DRAIN VOLTAGE (V) Figure 9. Diode Forward Voltage vs. Current

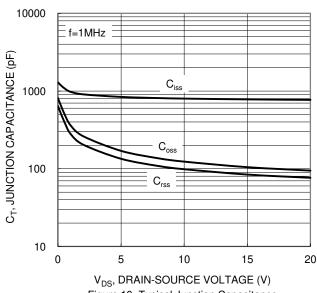
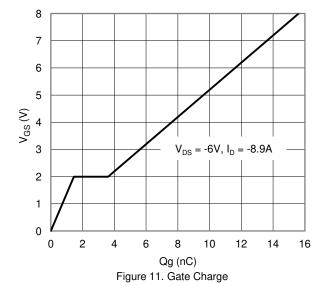


Figure 10. Typical Junction Capacitance



 $P_W = 100 \mu s$ 10 ID, DRAIN CURRENT (A) 1 P<sub>W</sub> =10ms  $P_W = 100 ms$ P<sub>w</sub> =1s 0.1  $T_{J(Max)} = 150\,^{\circ}\text{C}$   $T_{C} = 25\,^{\circ}\text{C}$  Single Pulse DUT on 1\*MRP Board DC  $V_{GS} = -4.5V$ 0.01 0.1 10 100  $V_{DS}$ , DRAIN-SOURCE VOLTAGE (V) Figure 12. SOA, Safe Operation Area

100

 $R_{DS(ON)}$  Limited



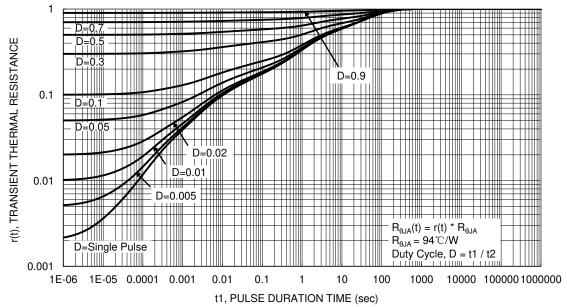


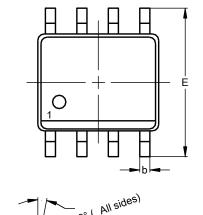
Figure 13. Transient Thermal Resistance

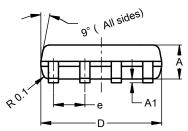


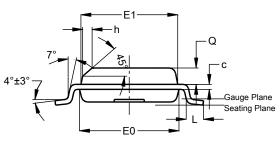
# **Package Outline Dimensions**

Please see http://www.diodes.com/package-outlines.html for the latest version.

SO-8



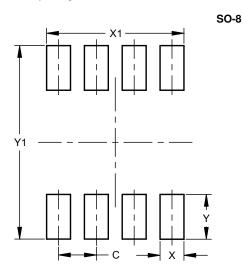




SO-8					
Dim	Min	Max	Тур.		
Α	1.40	1.50	1.45		
A1	0.10	0.20	0.15		
b	0.30	0.50	0.40		
С	0.15	0.25	0.20		
D	4.85	4.95	4.90		
Е	5.90	6.10	6.00		
E1	3.80	3.90	3.85		
E0	3.85	3.95	3.90		
e 1.27					
h 0.0					
L	0.62	0.82	0.72		
Q	0.60	0.70	0.65		
All Dimensions in mm					

# Suggested Pad Layout

Please see http://www.diodes.com/package-outlines.html for the latest version.



Dimensions	Value (in mm)				
С	1.27				
X	0.802				
X1	4.612				
Y	1.505				
V1	6 50				



#### IMPORTANT NOTICE

DIODES INCORPORATED MAKES NO WARRANTY OF ANY KIND, EXPRESS OR IMPLIED, WITH REGARDS TO THIS DOCUMENT, INCLUDING, BUT NOT LIMITED TO, THE IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION).

Diodes Incorporated and its subsidiaries reserve the right to make modifications, enhancements, improvements, corrections or other changes without further notice to this document and any product described herein. Diodes Incorporated does not assume any liability arising out of the application or use of this document or any product described herein; neither does Diodes Incorporated convey any license under its patent or trademark rights, nor the rights of others. Any Customer or user of this document or products described herein in such applications shall assume all risks of such use and will agree to hold Diodes Incorporated and all the companies whose products are represented on Diodes Incorporated website, harmless against all damages.

Diodes Incorporated does not warrant or accept any liability whatsoever in respect of any products purchased through unauthorized sales channel. Should Customers purchase or use Diodes Incorporated products for any unintended or unauthorized application, Customers shall indemnify and hold Diodes Incorporated and its representatives harmless against all claims, damages, expenses, and attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized application.

Products described herein may be covered by one or more United States, international or foreign patents pending. Product names and markings noted herein may also be covered by one or more United States, international or foreign trademarks.

This document is written in English but may be translated into multiple languages for reference. Only the English version of this document is the final and determinative format released by Diodes Incorporated.

#### **LIFE SUPPORT**

Diodes Incorporated products are specifically not authorized for use as critical components in life support devices or systems without the express written approval of the Chief Executive Officer of Diodes Incorporated. As used herein:

- A. Life support devices or systems are devices or systems which:
  - 1. are intended to implant into the body, or
  - 2. support or sustain life and whose failure to perform when properly used in accordance with instructions for use provided in the labeling can be reasonably expected to result in significant injury to the user.
- B. A critical component is any component in a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or to affect its safety or effectiveness.

Customers represent that they have all necessary expertise in the safety and regulatory ramifications of their life support devices or systems, and acknowledge and agree that they are solely responsible for all legal, regulatory and safety-related requirements concerning their products and any use of Diodes Incorporated products in such safety-critical, life support devices or systems, notwithstanding any devices- or systems-related information or support that may be provided by Diodes Incorporated. Further, Customers must fully indemnify Diodes Incorporated and its representatives against any damages arising out of the use of Diodes Incorporated products in such safety-critical, life support devices or systems.

Copyright © 2019, Diodes Incorporated

www.diodes.com